

L Number	Hits	Search Text	DB	Time stamp
2	144	(703/28).CCLS.	USPAT	2004/09/19 14:37
3	0	network and device and diagnostic\$2 and (ISC adj pins)	USPAT	2004/09/19 14:38
4	0	network and device and diagnostic\$2 and (ISC same pins)	USPAT	2004/09/19 14:38
5	48	network and device and diagnostic\$2 and ISC	USPAT	2004/09/19 14:39
6	730	diagnostic same embedded	USPAT	2004/09/19 14:40
7	25	(diagnostic same embedded) and JTAG	USPAT	2004/09/19 14:45
8	10	FPGA and remote and diagnostics and JTAG	USPAT	2004/09/19 14:54
9	1	BIST and diagnostic\$2 and FPGA and embedded and boundary and scan and testbench	USPAT	2004/09/19 14:54

Untitled

Krzysztof Badzmirowski et al., "Diagnosis of Digital/Analogue Measurement System with Application of Test Bus and Distributed Diagnostic Subsystem,"  
Proceedings of the IEEE Instrumentation and Measurement Technology Conference,  
1998.

**Results Key:**

**JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

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**1 Computer aided verification and diagnosis of distributed measurement systems**

*Badzmirowski, K.; Kern, J.; Liderman, K.; Zielinski, Z.;*

Instrumentation and Measurement Technology Conference, 1997. IMTC/97. Proceedings. 'Sensing, Processing, Networking'. IEEE , Volume: 2 , 19-21 May 1997

Pages:1195 - 1202 vol.2

IEEE CNF

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**2 The measurement quality verification process with application of distributed expert systems**

*Badzmirowski, K.; Kern, J.; Liderman, K.; Zielinski, Z.;*

Instrumentation and Measurement Technology Conference, 1996. IMTC-96. Conference Proceedings. 'Quality Measurements: The Indispensable Bridge between Theory and Reality'. IEEE , Volume: 2 , 1996

Pages:1226 - 1231 vol.2

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**3 The issue of diagnosis quality applied to a distributed system of digital signal microanalyzers, equipped with standard test ports**

*Badzmirowski, K.; Kern, J.;*

Instrumentation and Measurement Technology Conference, 1999. IMTC/99. Proceedings of the 16th IEEE , Volume: 1 , 24-26 May 1999

Pages:220 - 224 vol.1

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**4 Application of deterministic dither signals in digital voltmeter with sigma-delta oversampled A/D converter**

*Badzmirowski, K.; Jackiewicz, B.;*

Instrumentation and Measurement Technology Conference, 1999. IMTC/99. Proceedings of the 16th IEEE , Volume: 3 , 24-26 May 1999

Pages:1659 - 1662 vol.3

IEEE CNF

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**5 Diagnosis of digital/analogue measurement system with application of test bus and distributed diagnostic subsystem**

*Badzmirowski, K.; Gonera, M.; Kern, J.;*

Instrumentation and Measurement Technology Conference, 1998. IMTC/98. Conference Proceedings. IEEE , Volume: 1 , 18-21 May 1998

Pages:490 - 495 vol.1

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**6 Effects of noise dither signals on differential linearity and effective resolution of sigma-delta A/D converters in measuring applications**

*Badzmirowski, K.; Jackiewicz, B.;*

Instrumentation and Measurement Technology Conference, 1998. IMTC/98. Conference Proceedings. IEEE , Volume: 2 , 18-21 May 1998

Pages:1229 - 1232 vol.2

**7 Effectiveness of various dithering architectures for linearisation of high-resolution oversampling A/D converters**

*Badzmirowski, K.; Jackiewicz, B.;*

Advanced A/D and D/A Conversion Techniques and their Applications, 1999. Third International Conference on (Conf. Publ. No. 466) , 27-28 July 1999

Pages:175 - 178